

**Notice of References Cited**

Application/Control No.

09/827,688

Applicant(s)/Patent Under

Reexamination

ORSON ET AL.

Examiner

Quang Nguyen, Ph.D.

Art Unit

1636

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,348,449	02-2002	Weiner et al.	514/44
	B	US-			
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	L	US-			
	M	US-			

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	X	Denonarain, MP. Exp. Opin. Ther. Patents 8:53-69, 1998.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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